## **Power MOSFET**

# 30 V, 100 A, Single N-Channel, SO-8 FL

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Thermally Enhanced SO8 Package
- These are Pb-Free Device

### **Applications**

- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

## **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise stated)

- WAXINGWITATII	, -		Symbol		·
	Parameter			Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	30	V
Gate-to-Source Vol	Gate-to-Source Voltage			±20	V
Continuous Drain Current R <sub>0JA</sub>		T <sub>A</sub> = 25°C	Ι <sub>D</sub>	20.3	Α
(Note 1)		T <sub>A</sub> = 85°C		14.6	
Power Dissipation $R_{\theta JA}$ (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.25	W
Continuous Drain	]	T <sub>A</sub> = 25°C	I <sub>D</sub>	32.8	Α
Current $R_{\theta JA} \leq$ 10 sec		T <sub>A</sub> = 85°C		23.7	
Power Dissipation $R_{\theta JA,} t \leq 10 \text{ sec}$	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	5.90	W
Continuous Drain	State	T <sub>A</sub> = 25°C	Ι <sub>D</sub>	12.7	Α
Current R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 85°C		9.2	
Power Dissipation $R_{\theta JA}$ (Note 2)	]	T <sub>A</sub> = 25°C	P <sub>D</sub>	0.89	W
Continuous Drain	]	T <sub>C</sub> = 25°C	Ι <sub>D</sub>	100	Α
Current $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 85°C		72	
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	55.5	W
Pulsed Drain Current	t <sub>p</sub> =10μs	T <sub>A</sub> = 25°C	I <sub>DM</sub>	200	Α
Current limited by pa	ıckage	T <sub>A</sub> = 25°C	I <sub>Dmaxpkg</sub>	100	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C
Source Current (Body Diode)			I <sub>S</sub>	55	Α
Drain to Source dV/dt			dV/dt	6	V/ns
Single Pulse Drain–to–Source Avalanche Energy ( $V_{DD}$ = 50 V, $V_{GS}$ = 10 V, $I_{L}$ = 37 $A_{pk}$ , $L$ = 0.3 mH, $R_{G}$ = 25 $\Omega$ )			EAS	205	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1

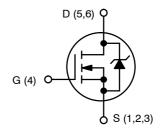


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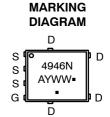
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX		
30 V	3.4 mΩ @ 10 V	100 4		
30 V	5.1 mΩ @ 4.5 V	100 A		



**N-CHANNEL MOSFET** 



STYLE 1



A = Assembly Location

Y = Year
WW = Work Week
= Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4946NT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4946NT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.25	
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	55.6	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	140.8	C/VV
Junction-to-Ambient - t ≤ 10 sec	$R_{ heta JA}$	21.2	DataShoot

- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>.I</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	<u></u>			ı			
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				25		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25 °C T <sub>J</sub> = 125°C			1 10	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub>	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D =$	= 250 μΑ	1.45	1.8	2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.2		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V to	I <sub>D</sub> = 30 A		2.5	3.4	
	11.5 V	I <sub>D</sub> = 15 A		2.4		1	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		3.8	5.1	mΩ
			I <sub>D</sub> = 15 A		3.8		1
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 30 A			85		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 12 V			3250		pF
Output Capacitance	C <sub>OSS</sub>				562		
Reverse Transfer Capacitance	C <sub>RSS</sub>				289		1
Total Gate Charge	Q <sub>G(TOT)</sub>				21.8	32	
Threshold Gate Charge	Q <sub>G(TH)</sub>	V 45VV 4	E \		3.2		]
Gate-to-Source Charge	$Q_{GS}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			8.1		nC
Gate-to-Drain Charge	$Q_{GD}$				7.4		
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS} = 11.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_D = 30 \text{ A}$			53		nC
SWITCHING CHARACTERISTICS (Note 4)							
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A},$ $R_{G} = 3.0 \Omega$			18.9		
Rise Time	t <sub>r</sub>				34		]
Turn-Off Delay Time	t <sub>d(OFF)</sub>				24.6		ns
Fall Time	t <sub>f</sub>				9.4		1

- 3. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.
- 4. Switching characteristics are independent of operating junction temperatures.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 4)						•
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 11.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			10.7		ns DataShee
Rise Time	t <sub>r</sub>				18.9		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				34.2	TAZ TAZTAZ	
Fall Time	t <sub>f</sub>				7.1		
DRAIN-SOURCE DIODE CHARACTE	ERISTICS				_		
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.8	1.0	V
		I <sub>S</sub> = 30 A	T <sub>J</sub> = 125°C		0.66		
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dI <sub>S</sub> /dt = 100 A/μs, I <sub>S</sub> = 30 A			21.6		
Charge Time	t <sub>a</sub>				11.4		ns
Discharge Time	t <sub>b</sub>				10.2		
Reverse Recovery Charge	Q <sub>RR</sub>				8.5		nC
PACKAGE PARASITIC VALUES					_		
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			0.65		nH
Drain Inductance	L <sub>D</sub>				0.005		1
Gate Inductance	L <sub>G</sub>				1.84		1
Gate Resistance	$R_{G}$			0.5	1.4	2.2	Ω

<sup>3.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.

## **TYPICAL CHARACTERISTICS**

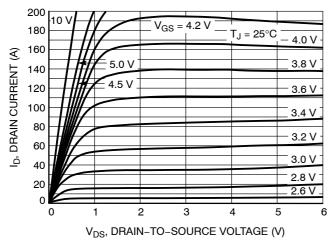


Figure 1. On-Region Characteristics

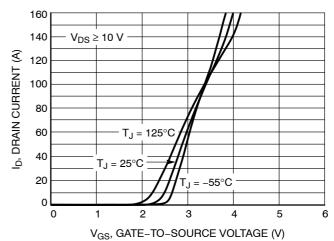
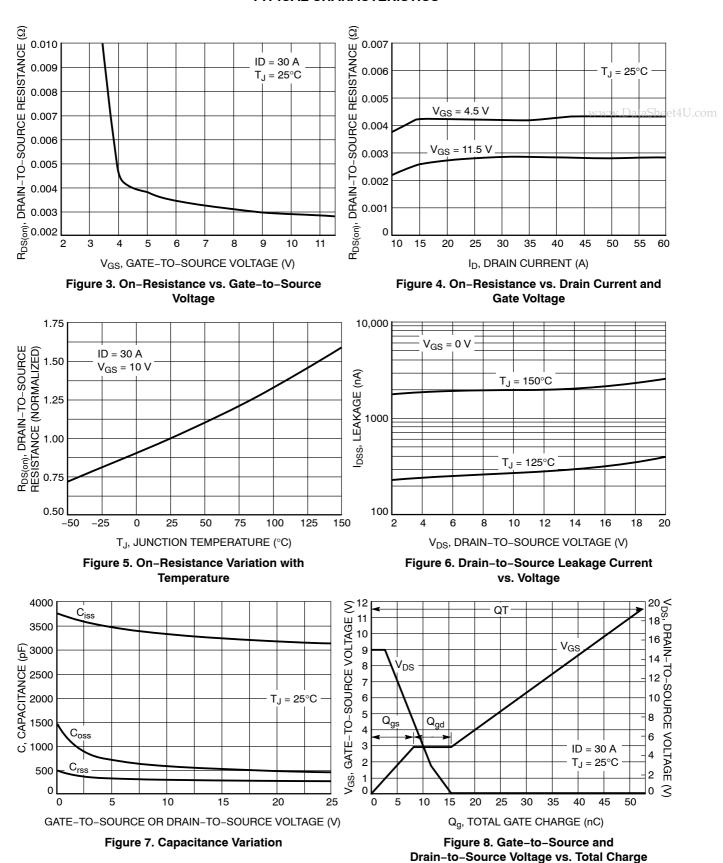


Figure 2. Transfer Characteristics

<sup>4.</sup> Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**



### **TYPICAL CHARACTERISTICS**

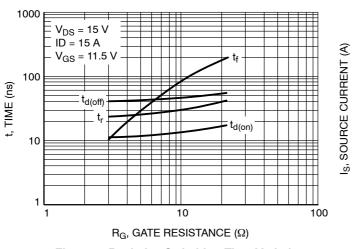


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

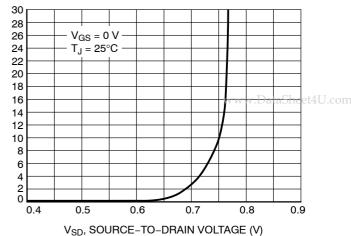


Figure 10. Diode Forward Voltage vs. Current

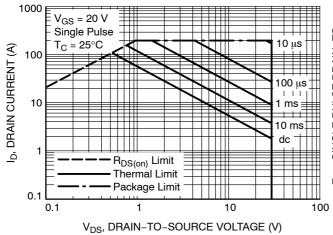


Figure 11. Maximum Rated Forward Biased Safe Operating Area

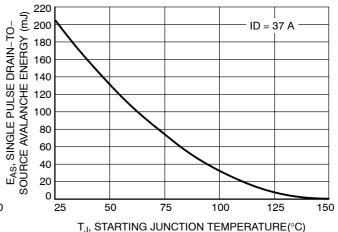


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

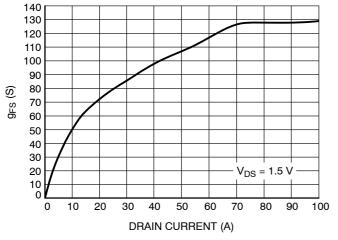


Figure 13. g<sub>FS</sub> vs. Drain Current

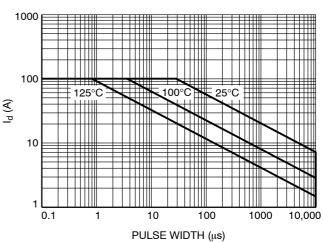
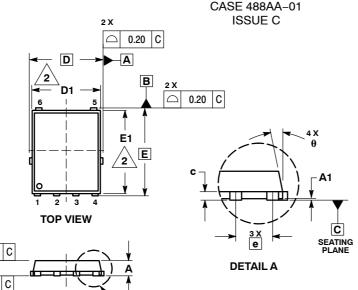


Figure 14. I<sub>d</sub> vs. Pulse Width

#### PACKAGE DIMENSIONS

## DFN6 5x6, 1.27P (SO8 FL)



STYLE 1: PIN 1. SOURCE 2. SOURCE

3. SOURCE 4. GATE

5. DRAIN 6. DRAIN

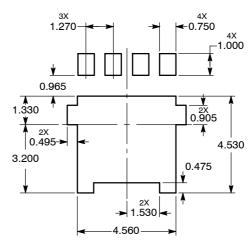
**DETAIL A** 

#### NOTES

- DIMENSIONING AND TOLERANCING PER
   ASME V14 FM 1994
- ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETER.
- 3. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS. www.DataSheet4U.com

	MILLIMETERS					
DIM	MIN	NOM	MAX			
Α	0.90	1.00	1.10			
A1	0.00		0.05			
b	0.33	0.41	0.51			
С	0.23	0.28	0.33			
D		5.15 BSC	;			
D1	4.50	4.90	5.10			
D2	3.50		4.22			
E		6.15 BSC	;			
E1	5.50	5.80	6.10			
E2	3.45		4.30			
е		1.27 BSC	;			
G	0.51	0.61	0.71			
K	0.51					
L	0.51	0.61	0.71			
L1	0.05	0.17	0.20			
M	3.00	3.40	3.80			
A	0 °		12 0			

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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